

<b>Notice of References Cited</b>	Application/Control No. 10/535,366		Applicant(s)/Patent Under Reexamination ABE ET AL.	
	Examiner AMY HSU		Art Unit 2622	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,319,225 A	06-1994	Kim, Beom-Shik	257/223
*	B	US-5,825,056 A	10-1998	Yonemoto, Kazuya	257/290
*	C	US-6,072,206 A	06-2000	Yamashita et al.	257/292
*	D	US-2001/0052941 A1	12-2001	Matsunaga et al.	348/308
*	E	US-6,383,860 B2	05-2002	Maeda et al.	438/239
*	F	US-2002/0122130 A1	09-2002	Yamaguchi et al.	348/308
*	G	US-6,606,122 B1	08-2003	Shaw et al.	348/302
*	H	US-6,674,470 B1	01-2004	Tanaka et al.	348/302
*	I	US-7,113,213 B2	09-2006	Matsunaga et al.	348/308
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.